## Notice of References Cited Application/Control No. 10/574,319 Examiner GREG BENGZON Applicant(s)/Patent Under Reexamination SUN ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,983,334 B2	01-2006	Riedle, Linda Ann	709/250
*	В	US-6,185,623 B1	02-2001	Bailey et al.	709/238
*	C	US-2008/0168157 A1	07-2008	Marchand, Benoit	709/219
*	D	US-7,305,585 B2	12-2007	Marchand, Benoit	714/18
*	Е	US-2003/0088667 A1	05-2003	Riedle, Linda Ann	709/224
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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